

Shenzhen Zhongjian Nanfang Testing Co., Ltd.

Report No: CCISE180605201

FCC REPORT

(GSM & WCDMA)

Applicant: Sun Cupid Technology (HK) Ltd.

Address of Applicant: 16/F, CEO Tower, 77 Wing Hong Street, Cheung Sha Wan,

Kowloon, Hong Kong.

Equipment Under Test (EUT)

Product Name: LTE mobile phone

Model No.: N5501L, A5L

Trade mark: NUU

FCC ID: 2ADINN5501L

FCC CFR Title 47 Part 2

Applicable standards: FCC CFR Title 47 Part 22 Subpart H

FCC CFR Title 47 Part 24 Subpart E

FCC CFR Title 47 Part 27 Subpart L

Date of sample receipt: 20 Jun., 2018

Date of Test: 20 Jun., to 16 Jul., 2018

Date of report issued: 25 Jul., 2018

Test Result: PASS*

* In the configuration tested, the EUT complied with the standards specified above.

Authorized Signature:



Bruce Zhang Laboratory Manager

This report details the results of the testing carried out on one sample. The results contained in this test report do not relate to other samples of the same product and does not permit the use of the CCIS product certification mark. The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report.

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2. Version

Version No.	Date	Description
00	25 Jul., 2018	Original

Tested by: Date: 25 Jul., 2018

Test Engineer

Reviewed by: Date: 25 Jul., 2018

Project Engineer



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4. Test Summary

Part 1.1307 Part 2.1093 Part 2.1046 Part 22.913 (a)(2)	Pass (Please refer to SAR Report)
Part 24.232 (c) Part 27.50 (d)(4)	Pass
Part 24.232 (d) Part 27.50(d)(5)	Pass
Part 2.1047	Pass
Part 2.1049 Part 22.917(b) Part 24.238(b) Part 27.53(h)	Pass
Part 2.1051 Part 22.917 (a) Part 24.238 (a) Part 27.53 (h)	Pass
Part 2.1053 Part 22.917 (a) Part 24.238 (a) Part 27.53 (h)	Pass
Part 22.917 (a) Part 24.238 (a) Part 27.53 (h)	Pass
Part 22.355 Part 24.235 Part 27.54 Part 2.1055(a)(1)(b)	Pass
Part 22.355 Part 24.235 Part 27.54 Part 2.1055(d)(2)	Pass
	Part 27.50 (d)(4) Part 24.232 (d) Part 27.50(d)(5) Part 2.1047 Part 2.1049 Part 22.917(b) Part 24.238(b) Part 27.53(h) Part 22.917 (a) Part 24.238 (a) Part 27.53 (h) Part 21.053 Part 27.53 (h) Part 24.238 (a) Part 24.238 (a) Part 27.53 (h) Part 24.238 (a) Part 27.53 (h) Part 27.53 (h) Part 27.53 (h) Part 22.917 (a) Part 27.53 (h) Part 22.917 (a) Part 27.53 (h) Part 27.54 Part 27.54 Part 27.55 Part 24.235 Part 24.235 Part 24.235 Part 27.54





5. General Information

5.1 Client Information

Applicant:	Sun Cupid Technology (HK) Ltd.
Address:	16/F, CEO Tower, 77 Wing Hong Street, Cheung Sha Wan, Kowloon, Hong Kong.
Manufacturer	Sun Cupid Technology (HK) Ltd.
Address:	16/F, CEO Tower, 77 Wing Hong Street, Cheung Sha Wan, Kowloon, Hong Kong.
Factory:	SUNCUPID (ShenZhen) Electronic. Ltd.
Address:	Baolong Industrial City, Longgang District, Shenzhen Hi-Tech Road, Building 1, A 7, China.

5.2 General Description of E.U.T.

Product Name:	LTE mobile phone
Model No.:	N5501L, A5L
Operation Frequency range:	GSM 850: 824.20MHz-848.80MHz PCS1900: 1850.20MHz-1909.80MHz WCDMA Band V: 826.4MHz-846.6MHz WCDMA Band II: 1852.4 MHz-1907.6 MHz WCDMA Band IV: 1712.4 MHz-1752.6 MHz
Modulation type:	GSM/GPRS: GMSK, UMTS: QPSK, EGPRS: 8PSK
Antenna type:	Internal Antenna
Antenna gain:	GSM 850: -0.67 dBi PCS 1900: 0.03 dBi WCDMA Band V: 0.67 dBi WCDMA Band II: 0.03 dBi WCDMA Band IV: 0.4 dBi
Power supply:	Rechargeable Li-ion Battery DC3.8V-2650mAh
AC adapter:	Adapter(1) Model: HNBL050100UX Input: AC100-240V, 50/60Hz, 0.2A Output: DC 5.0V, 1.0A Adapter(2) Model: HJ-0501000E1-US Input: AC100-240V, 50/60Hz, 0.2A Output: DC 5.0V, 1.0A Adapter(3) Model: HJ-0501000B3-EU Input: AC100-240V, 50/60Hz, 0.2A Output: DC 5.0V, 1.0A
Remark:	 The No.: N5501L, A5L were identical inside, the electrical circuit design, layout, components used and internal wiring, with only difference being model name and trademark. adapter(1) have different pins and the internal structure is the same, so there is no need to do the difference test.





Operation Frequency List:

peration Frequency List:				
	GSM 850		\$1900	
Channel	Frequency (MHz)	Channel	Frequency (MHz)	
128	824.20	512	1850.20	
129	824.40	513	1850.40	
189	836.40	660	1879.80	
190	836.60	661	1880.00	
191	836.80	662	1880.20	
250	848.60	809	1909.60	
251	848.80	810	1909.80	
WCDM.	A Band V	WCDM	IA Band II	
Channel	Frequency (MHz)	Channel	Frequency (MHz)	
4132	826.40	9262	1852.40	
4133	826.60	9263	1852.60	
4182	836.40	9399	1879.80	
4183	836.60	9400	1880.00	
4184	836.80	9401	1880.20	
4232	846.40	9537	1907.40	
4233	846.60	9538	1907.60	
WCDM	A Band IV			
Channel	Frequency (MHz)			
1312	1712.40			
1313	1712.60			
1412	1732.40			
1413	1732.60			
1414	1732.80			
1512	1752.40			
1513	1752.60			

Regards to the operating frequency range over 10 MHz, the Lowest frequency, the middle frequency, and the highest frequency of channel were selected to perform the test, and the selected channel see below:

	GSM850		PCS1900		
Channel		Frequency(MHz)	Channel		Frequency(MHz)
Lowest channel	128	824.20	Lowest channel	512	1850.20
Middle channel	190	836.60	Middle channel	661	1880.00
Highest channel	251	848.80	Highest channel	810	1909.80
1	WCDMA Band V	/	•	WCDMA Band I	
Chann	iel	Frequency(MHz)	Channel		Frequency(MHz)
Lowest channel	4132	826.40	Lowest channel	9262	1852.40
Middle channel	4183	836.60	Middle channel	9400	1880.00
Highest channel	4233	846.60	Highest channel	9538	1907.60
WCDMA Band IV					
Channel		Frequency(MHz)			
Lowest channel	1312	1712.40			
Middle channel	1413	1732.60			
Highest channel	1513	1752.60			

Bao'an District, Shenzhen, Guangdong, China

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5.3 Test modes

Operating Environmen	Operating Environment:		
Temperature:	Normal: 15°C ~ 35°C, Extreme: -30°C ~ +50°C		
Humidity:	20 % ~ 75 % RH		
Atmospheric Pressure:	1008 mbar		
Voltage:	Nominal: 3.8Vdc, Extreme: Low 3.5 Vdc, High 4.35 Vdc		
Test mode:			
GSM mode	Keep the EUT communication with simulated station in GSM mode		
GPRS mode	Keep the EUT communication with simulated station in GPRS mode		
EGPRS mode	Keep the EUT communication with simulated station in EGPRS mode		
RMC mode	Keep the EUT communication with simulated station in RMC mode		
HSDPA	Keep the EUT communication with simulated station in HSDPA mode		
HSUPA	Keep the EUT communication with simulated station in HSUPA mode		

Remark: The EUT has been tested under continuous transmitting mode. Channel Low, Mid and High for each type band with rated data rate were chosen for full testing. The field strength of spurious radiation emission was measured as EUT stand-up position (H mode) and lie down position (E1, E2 mode) for these modes with power adaptor, earphone and Data cable. Just the worst case position (H mode) shown in report.

5.4 Description of Support Units

Test Equipment	Manufacturer	Model No.	Serial No.	
Simulated Station	Anritsu	MT8820C	6201026545	

5.5 Measurement Uncertainty

Parameters	Expanded Uncertainty
Radiated Emission (9kHz ~ 30MHz)	±2.76 dB (k=2)
Radiated Emission (30MHz ~ 1000MHz)	±4.28 dB (k=2)
Radiated Emission (1GHz ~ 18GHz)	±5.72 dB (k=2)
Radiated Emission (18GHz ~ 40GHz)	±2.88 dB (k=2)

5.6 Laboratory Facility

The test facility is recognized, certified, or accredited by the following organizations:

FCC - Registration No.: 727551

Shenzhen Zhongjian Nanfang Testing Co., Ltd. has been accredited as a testing laboratory by FCC (Federal Communications Commission). The Registration No. is 727551.

IC - Registration No.: 10106A-1

The 3m Semi-anechoic chamber of Shenzhen Zhongjian Nanfang Testing Co., Ltd. has been Registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 10106A-1.

CNAS - Registration No.: CNAS L6048

Shenzhen Zhongjian Nanfang Testing Co., Ltd. is accredited to ISO/IEC 17025:2005 General Requirements for the Competence of Testing and Calibration laboratories for the competence of testing. The Registration No. is CNAS L6048.

A2LA - Registration No.: 4346.01

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 General requirements for the competence of testing and calibration laboratories. The test scope can be found as below link: https://portal.a2la.org/scopepdf/4346-01.pdf

Shenzhen Zhongjian Nanfang Testing Co., Ltd.
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5.7 Laboratory Location

Shenzhen Zhongjian Nanfang Testing Co., Ltd.

Address: No. B-C, 1/F., Building 2, Laodong No.2 Industrial Park, Xixiang Road,

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Email: info@ccis-cb.com, Website: http://www.ccis-cb.com

5.8 Test Instruments list

Test Equipment	Manufacturer	Model No.	Serial No.	Cal. Date (mm-dd-yy)	Cal. Due date (mm-dd-yy)
3m SAC	SAEMC	9m*6m*6m	966	07-22-2017	07-21-2020
BiConiLog Antenna	SCHWARZBECK	VULB9163	497	03-16-2018	03-15-2019
Biconical Antenna	SCHWARZBECK	VUBA9117	359	06-22-2017	06-21-2018
Diconical Antenna	SCHWARZBECK	VOBASTIT	359	06-22-2018	06-21-2019
Horn Antenna	SCHWARZBECK	BBHA9120D	916	03-16-2018	03-15-2019
Horn Antenna	SCHWARZBECK	BBHA9120D	1805	03-16-2018	03-15-2019
EMI Test Software	AUDIX	E3	6.110919b	N/A	N/A
Pre-amplifier	HP	8447D	2944A09358	03-07-2018	03-06-2019
Pre-amplifier	CD	PAP-1G18	11804	03-07-2018	03-06-2019
Spectrum analyzer	Rohde & Schwarz	FSP30	101454	03-07-2018	03-06-2019
EMI Test Receiver	Rohde & Schwarz	ESRP7	101070	03-07-2018	03-06-2019
Spectrum Analyzer	Agilent	N9020A	MY50510123	10-29-2017	10-28- 2018
Signal Generator	Rohde & Schwarz	SMX	835454/016	03-07-2018	03-06-2019
Signal Generator	R&S	SMR20	1008100050	03-07-2018	03-06-2019
RF Switch Unit	MWRFTEST	MW200	N/A	N/A	N/A
Cable	ZDECL	Z108-NJ-NJ-81	1608458	03-07-2018	03-06-2019
Cable	MICRO-COAX	MFR64639	K10742-5	03-07-2018	03-06-2019
Cable	SUHNER	SUCOFLEX100	58193/4PE	03-07-2018	03-06-2019
DC Power Supply	XinNuoEr	WYK-10020K	1409050110020	10-31-2017	10-30-2018
Temperature Humidity Chamber	HengPu	HPGDS-500	20140828008	09-24-2017	09-23-2018
Simulated Station	Rohde & Schwarz	CMW500	140493	06-24-2017	06-23-2018
Simulated Station	Runde & Schwarz	CIVIVV500	140493	06-24-2018	06-23-2019



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6. Test results

6.1 Conducted Output Power

Test Requirement:	FCC part 22.913(a)(2), FCC part 24.232(c), FCC part 27.50(d)(4)		
Test Method:	ANSI/TIA-603-D 2010		
Limit:	GSM 850: 7W, PCS 1900: 2W		
	WCDMA Band V: 7W, WCDMA Band II: 2W, WCDMA Band IV: 1W		
Test setup:	System simulator ATT EUT		
Test Procedure:	The transmitter output was connected to a calibrated attenuator, the other end of which was connected to the simulated station. Transmitter output power was read off in dBm.		
Test Instruments:	Refer to section 5.8 for details		
Test mode:	Refer to section 5.3 for details		
Test results:	Passed		





Measurement Data:

Measurement Data:	Rure	st Average power (dE	3m)	
EUT Mode	128	190	251	Limit(dBm)
LOT WIOGO	824.20MHz	836.60MHz	848.80MHz	Ziiiii(aBiii)
GSM 850	31.98	32.15	32.27	
GPRS 850 (1 Uplink slot)	31.92	32.12	32.21	
GPRS 850 (2 Uplink slot)	31.01	31.15	31.29	
GPRS 850 (3 Uplink slot)	29.08	29.16	29.28	
GPRS 850 (4 Uplink slot)	27.95	28.04	28.12	38.45
EGPRS 850 (1 Uplink slot)	25.72	25.63	25.59	
EGPRS 850 (2 Uplink slot)	24.41	24.37	24.29	
EGPRS 850 (3 Uplink slot)	22.03	22.03	21.89	
EGPRS 850 (4 Uplink slot)	20.83	20.77	20.69	
	Burst Average power (dBm)			
EUT Mode	512	661	810	Limit(dBm)
	1850.20MHz	1880.00MHz	1909.80MHz	
PCS 1900	28.96	29.30	29.57	
GPRS 1900 (1 Uplink slot)	28.95	29.25	29.52	
GPRS 1900 (2 Uplink slot)	28.08	28.30	28.54	
GPRS 1900 (3 Uplink slot)	26.40	26.56	26.82	
GPRS 1900 (4 Uplink slot)	25.29	25.47	25.76	33.00
EGPRS 1900 (1 Uplink slot)	24.83	24.96	24.83	
EGPRS 1900 (2 Uplink slot)	23.45	23.52	23.38	
EGPRS 1900 (3 Uplink slot)	21.21	21.25	21.02	
EGPRS 1900 (4 Uplink slot)	19.80	19.84	19.60	



		Burst Average power (dBm)			
EUT Mode		4132	4183	4233	Limit(dBm)
		826.40MHz	836.60MHz	846.60MHz	, ,
	Subtest 1	22.30	22.15	22.13	
	Subtest 2	21.84	21.67	21.73	
UMTS 850 HSDPA	Subtest 3	20.50	20.40	20.26	
	Subtest 4	20.30	20.21	20.10	
	Subtest 1	21.73	21.64	21.58	
	Subtest 2	22.21	22.05	22.01	38.45
UMTS 850 HSUPA	Subtest 3	19.65	19.72	19.60	
	Subtest 4	22.26	22.13	22.07	
	Subtest 5	20.81	20.78	20.67	
UMTS 850 RMC	12.2kbps	23.29	23.15	23.09	
UMTS 850 AMR	12.2kbps	23.28	23.14	23.08	
	·	Burs	Average power (d	dBm)	
EUT Mode	e	9262	9400	9538	Limit(dBm)
		1852.40MHz	1880.00MHz	1907.60MHz	, ,
	Subtest 1	21.55	21.13	21.43	
LIMTO 4000 LIODDA	Subtest 2	21.16	20.73	21.03	
UMTS 1900 HSDPA	Subtest 3	19.60	19.15	19.59	
	Subtest 4	19.55	19.13	19.47	
	Subtest 1	21.01	20.65	20.96	
	Subtest 2	21.47	21.02	21.33	33.00
UMTS 1900 HSUPA	Subtest 3	18.90	18.67	19.09	
	Subtest 4	21.47	21.05	21.39	
	Subtest 5	20.04	19.67	19.68	
UMTS 1900 RMC	12.2kbps	22.56	22.13	22.43	
UMTS 1900 AMR	12.2kbps	22.55	22.12	22.42	
		Burs	t Average power (d	dBm)	
EUT Mode	Э	1312	1412	1513	Limit(dBm)
		1712.40MHz	1732.40MHz	1752.60MHz	
	Subtest 1	22.60	22.43	22.34	
LIMTO 4700 LICODA	Subtest 2	22.15	22.02	21.92	
UMTS 1700 HSDPA	Subtest 3	20.70	20.53	20.33	
	Subtest 4	20.84	20.58	20.46	
UMTS 1700 HSUPA	Subtest 1	22.10	21.94	21.80	
	Subtest 2	22.52	22.35	22.22	33.00
	Subtest 3	20.21	20.00	19.82	
	Subtest 4	22.55	22.38	22.32	
	Subtest 5	21.04	20.93	20.88	
UMTS 1700 RMC	12.2kbps	23.60	23.41	23.35	
UMTS 1700 AMR	12.2kbps	23.58	23.40	23.33	



6.2 Occupy Bandwidth

Test Requirement:	FCC part 22.917(b), FCC part 24.238(b), FCC Part 27.53(h)	
Test Method:	ANSI/TIA-603-D 2010	
Test setup:	System simulator Splitter ATT EUT Spectrum Analyzer	
Test Procedure:	 The EUT's output RF connector was connected with a short cable to the spectrum analyzer RBW was set to about 1% of emission BW, VBW= 3 times RBW. -26dBc display line was placed on the screen (or 99% bandwidth), the occupied bandwidth is the delta frequency between the two points where the display line intersects the signal trace. 	
Test Instruments:	Refer to section 5.8 for details	
Test mode:	Refer to section 5.3 for details	
Test results:	Passed	





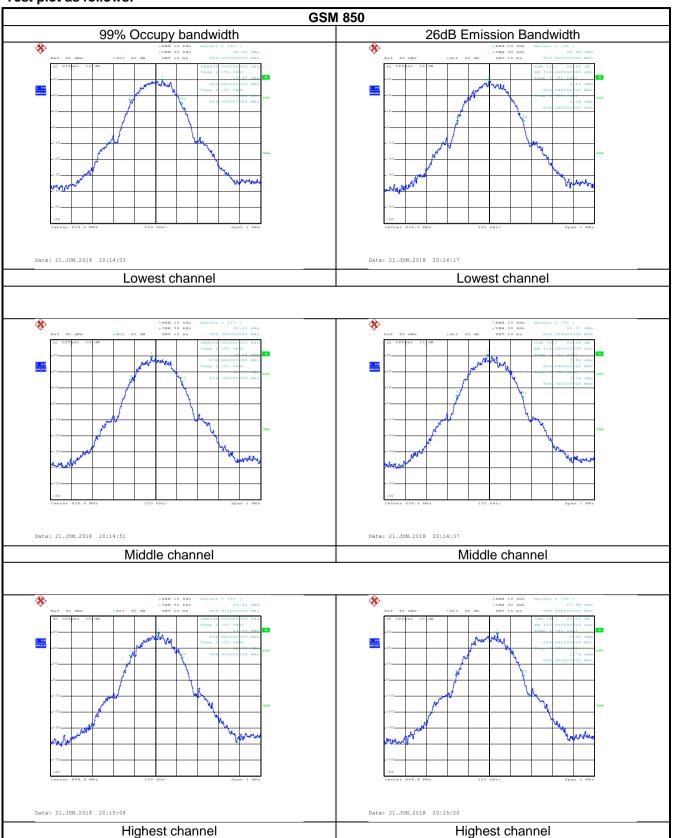
Measurement Data:

EUT Mode	Channel	Frequency (MHz)	99% Occupy bandwidth (kHz)	-26dB bandwidth (kHz)
	128	824.2	244	314
GSM 850	190	836.6	244	314
	251	848.8	246	320
	128	824.2	248	318
EGPRS850	190	836.6	244	320
	251	848.8	248	308
	512	1850.2	250	320
PCS 1900	661	1880.0	248	314
	810	1909.8	244	314
EGPRS1900	512	1850.2	248	312
	661	1880.0	244	318
	810	1909.8	246	318
LINATO 050	4132	826.4	4160	4740
UMTS 850 12.2k RMC	4183	836.6	4180	4740
	4233	846.6	4180	4740
	9262	1852.4	4180	4760
UMTS 1900 12.2k RMC	9400	1880.0	4180	4740
	9538	1907.6	4200	4740
LINATO 4706	1312	1712.40	4200	4720
UMTS 1700 12.2k RMC	1413	1732.60	4200	4780
	1513	1752.60	4180	4720

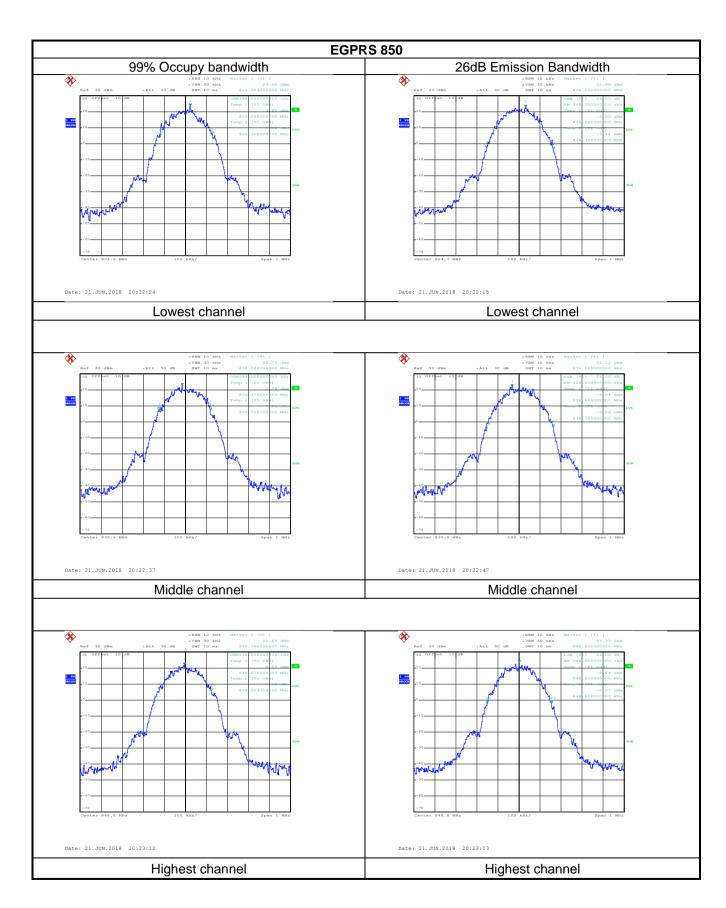
Note: GSM & GPRS use the same modulation technical (GMSK), and with the same channels, so the 99% OBW and the -26dB of GPRS not performed.



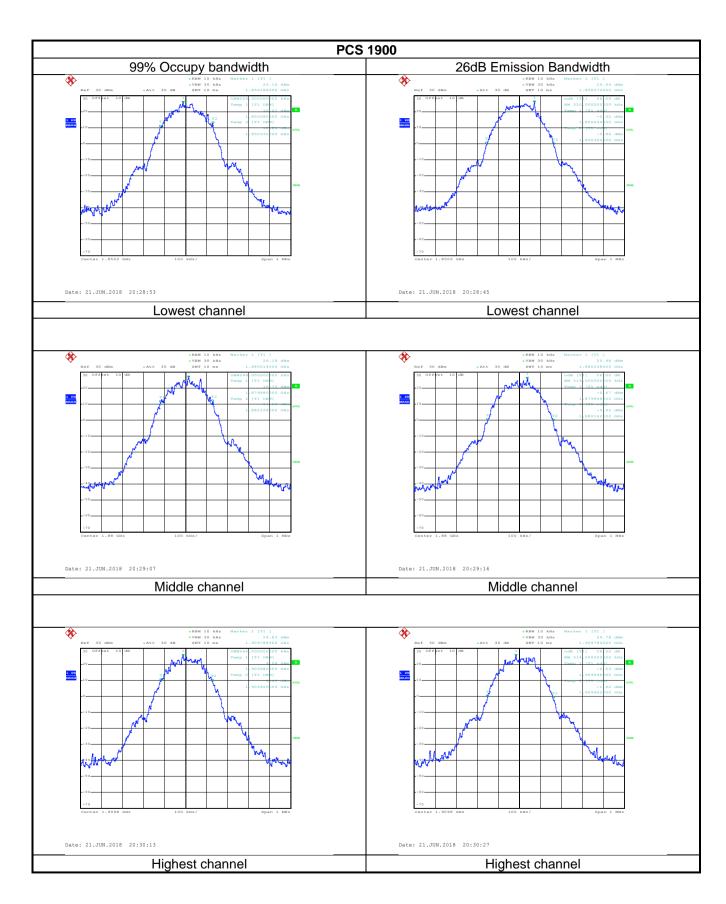
Test plot as follows:



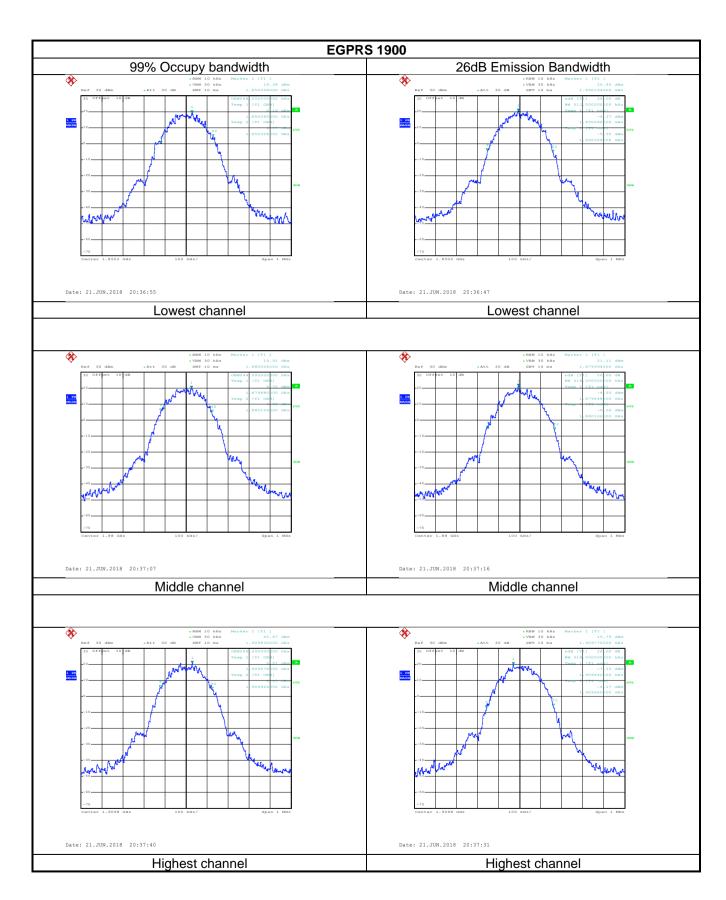




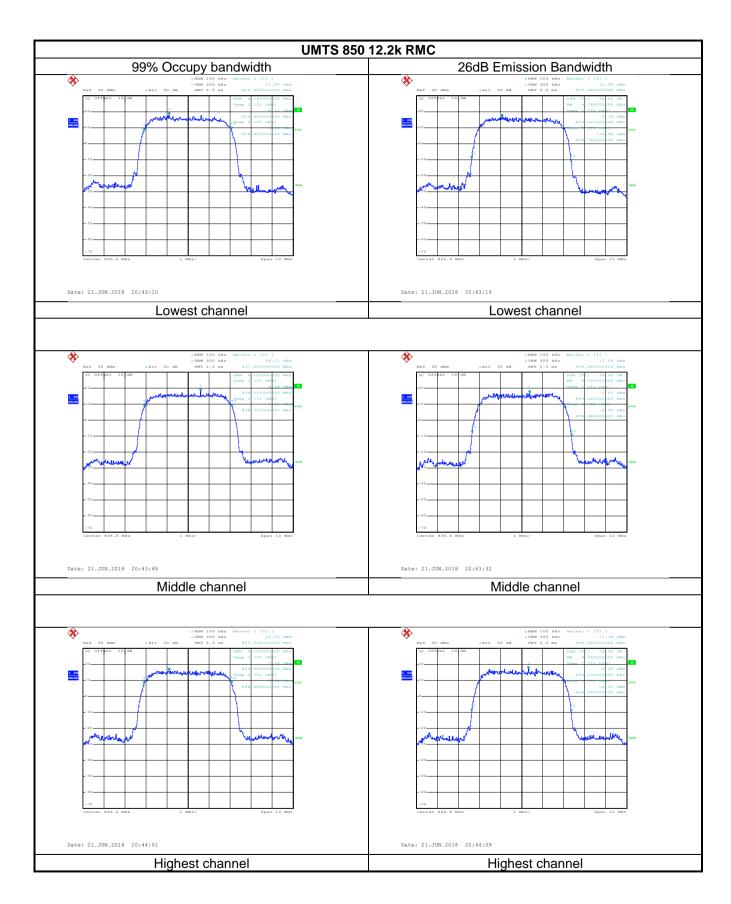




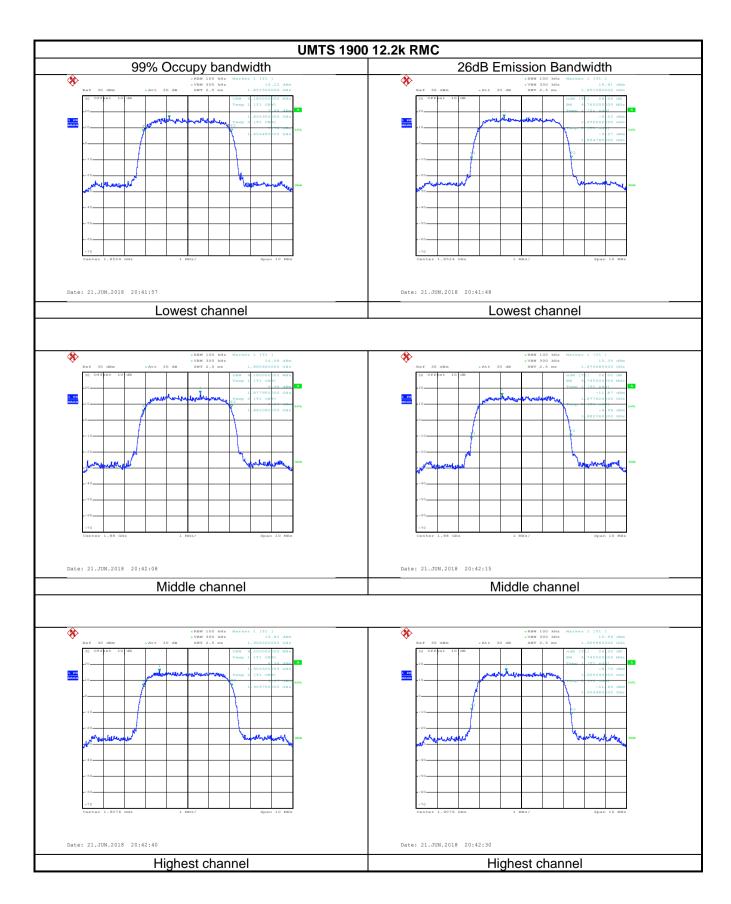




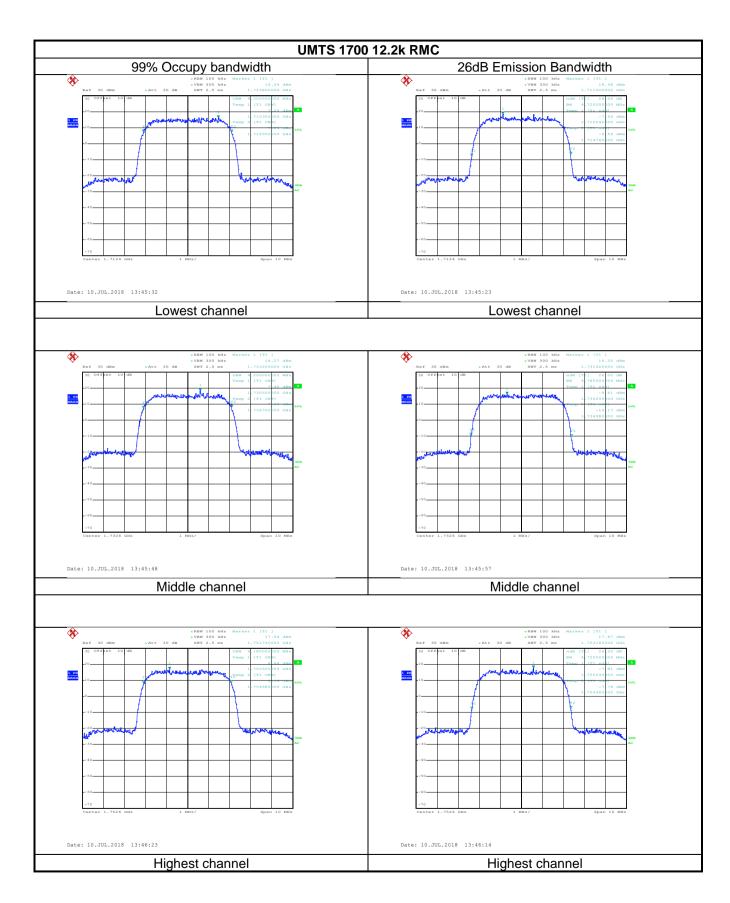














6.3 Peak-to-Average Power Ratio

Test Requirement:	FCC part 24.232(d), FCC part 27.50(d)(5)		
Test Method	ANSI/TIA-603-D 2010		
Limit:	The peak-to-average ratio (PAR) of the transmission may not exceed 13 dB.		
Test setup:	System simulator Spectrum Analyzer		
Test Procedure:	 The RF output of the transceiver was connected to a spectrum analyzer through appropriate attenuation. Set the CCDF option in spectrum analyzer, RBW ≥ OBW, Set the EUT working in highest power level, measured and recorded the 0.1% as PAPR level. Repeat step 1~3 at other frequency and modulations. 		
Test Instruments:	Refer to section 5.8 for details		
Test mode:	Refer to section 5.3 for details		
Test results:	Passed		

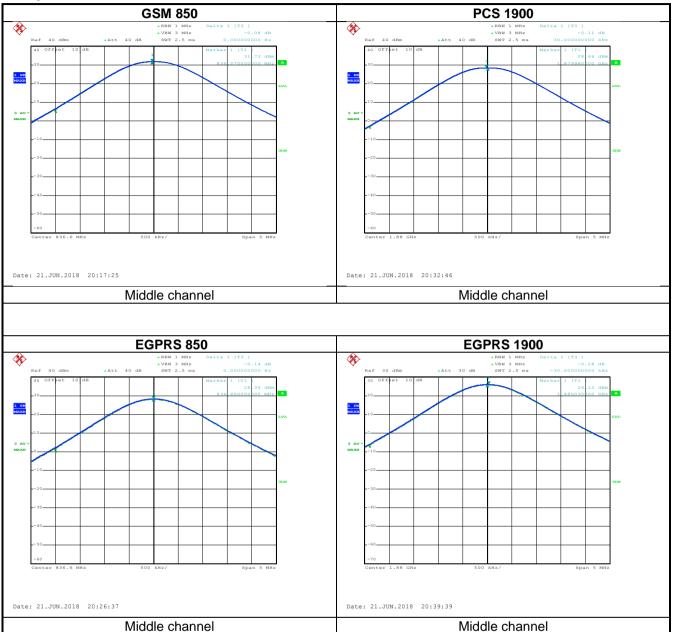
Measurement Data:

Modulation	Test channel	PAPR
GSM 850	190	0.08
EGPRS 850	190	0.14
PCS 1900	661	0.11
EGPRS 1900	661	0.28
UMTS 850 RMC	4183	2.88
UMTS 1900 RMC	9400	2.96
UMTS1700 RMC	1413	2.52

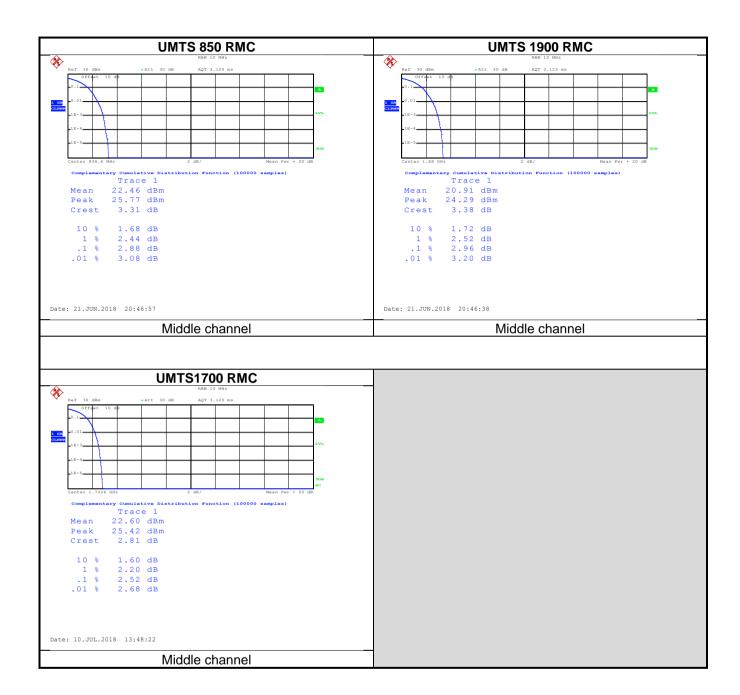




Test plots as below:









6.4 Modulation Characteristic

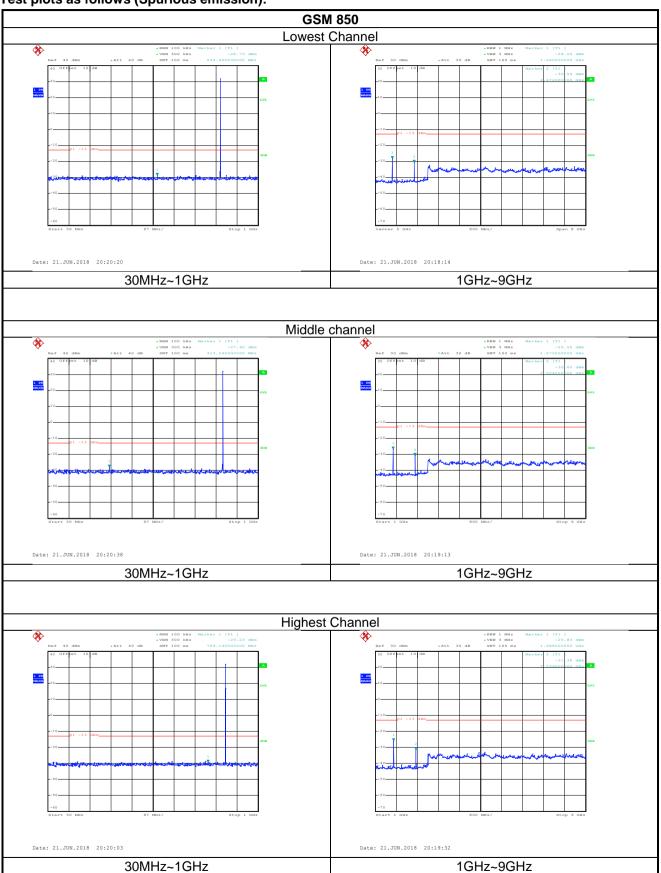
According to FCC § 2.1047(d), Part 22H & 24E & 27L there is no specific requirement for digital modulation, therefore modulation characteristic is not presented.

6.5 Out of band emission at antenna terminals

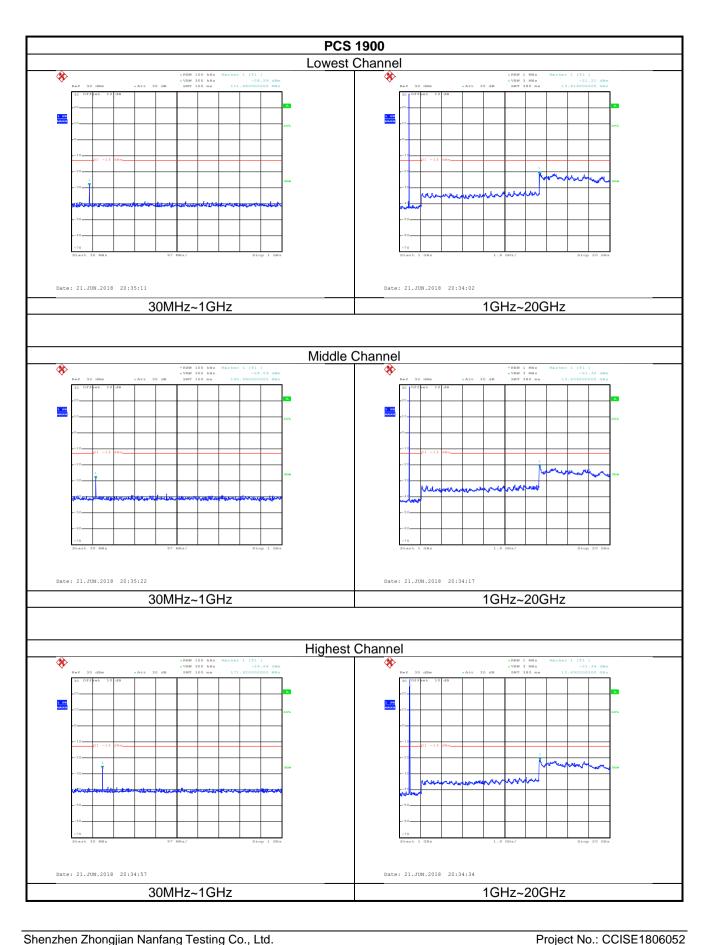
Test Requirement:	FCC part 22.917(a), FCC part 24.238(a), FCC Part 27.53 (h)	
Test Method:	ANSI/TIA-603-D 2010	
Limit:	-13dBm	
Test setup:	System simulator Splitter ATT EUT Spectrum Analyzer	
Test Procedure:	 The RF output of the transceiver was connected to a spectrum analyzer through appropriate attenuation. The resolution bandwidth of the spectrum analyzer was set at 100 kHz when below 1GHz, 1MHz when above 1 GHz; sufficient scans were taken to show the out of band Emissions if any up to 10th harmonic. For the out of band: Set the RBW=100 kHz, VBW=300 kHz when below 1 GHz, RBW =1 MHz, VBW=3 MHz when above 1 GHz, Start=30MHz, Stop= 10th harmonic. Band Edge Requirements: In the 1 MHz bands immediately outside and adjacent to the frequency block, a resolution bandwidth of at least 1 percent of the emission bandwidth of the fundamental emission of the transmitter may be employed to measure the out of band Emissions. 	
Test Instruments:	Refer to section 5.8 for details	
Test mode:	Refer to section 5.3 for details	
Test results:	Passed	



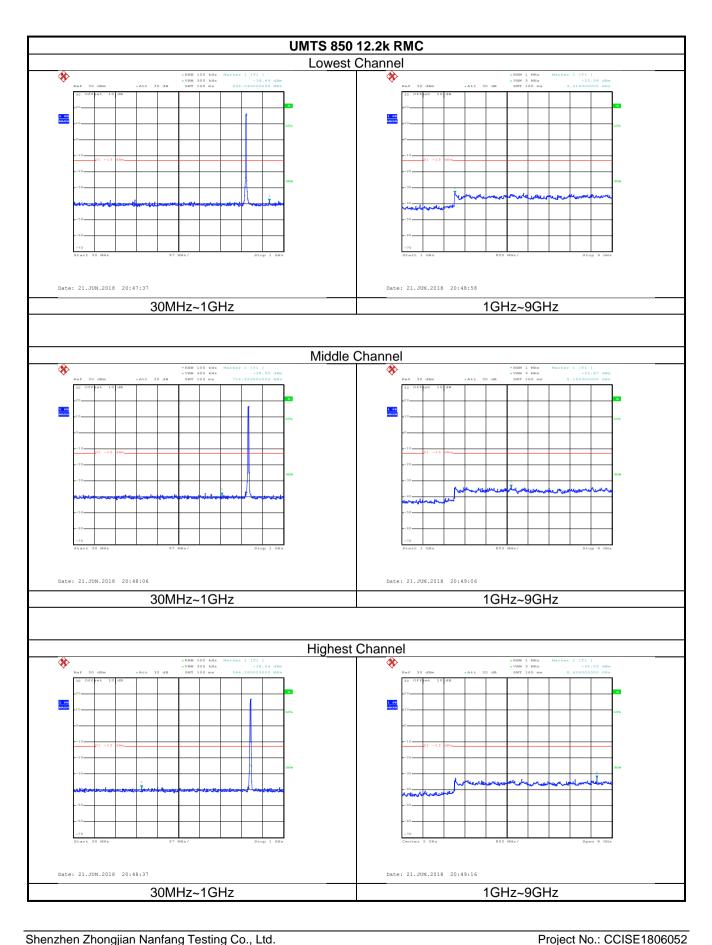
Test plots as follows (Spurious emission):



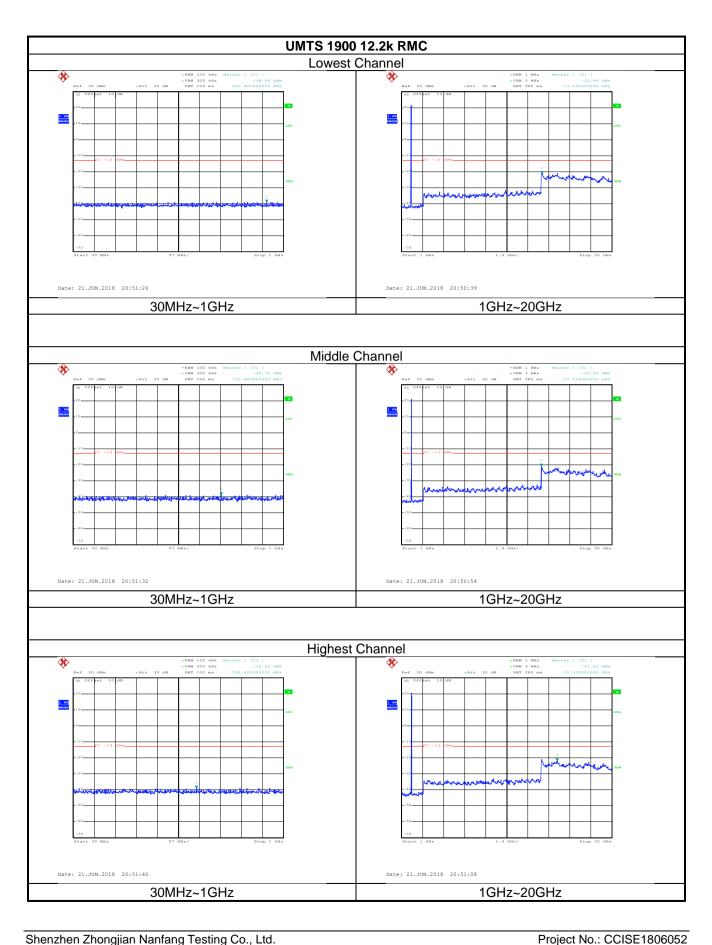




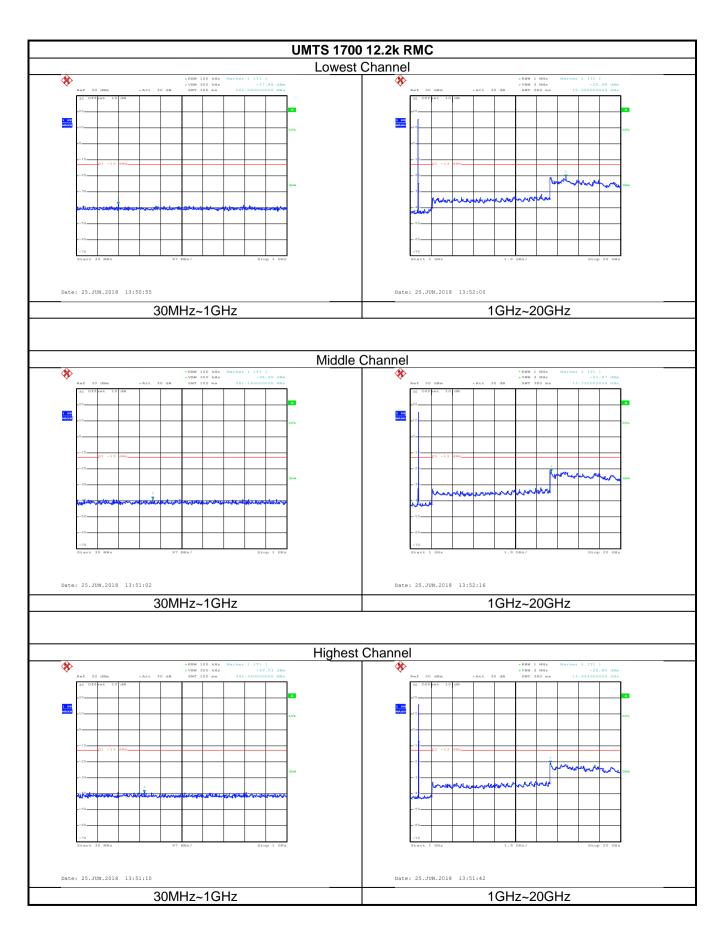








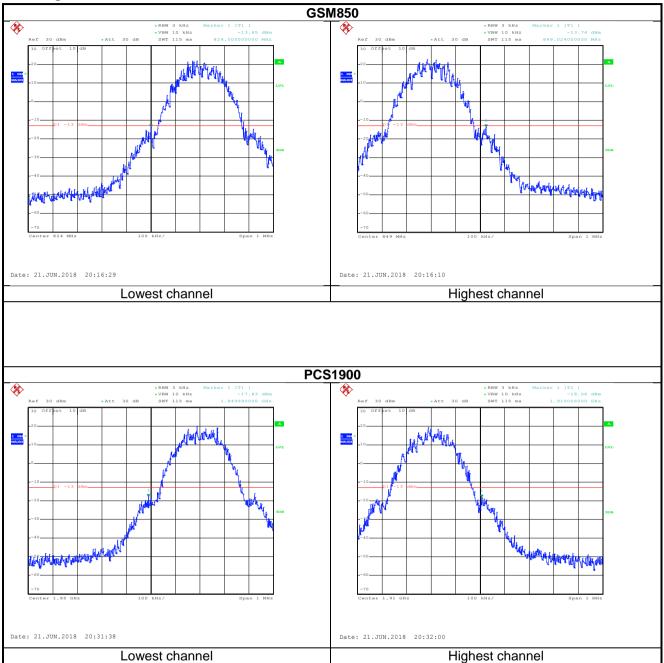




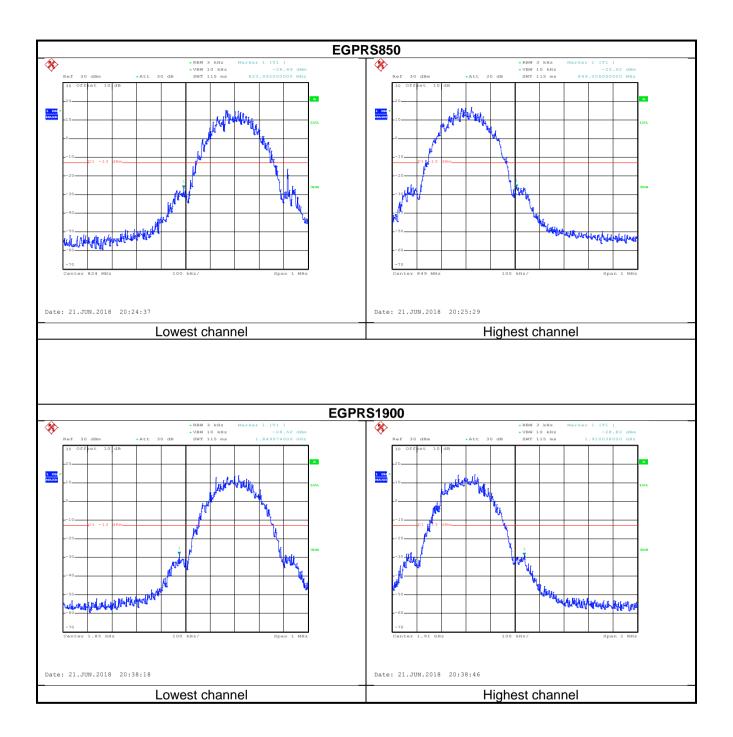




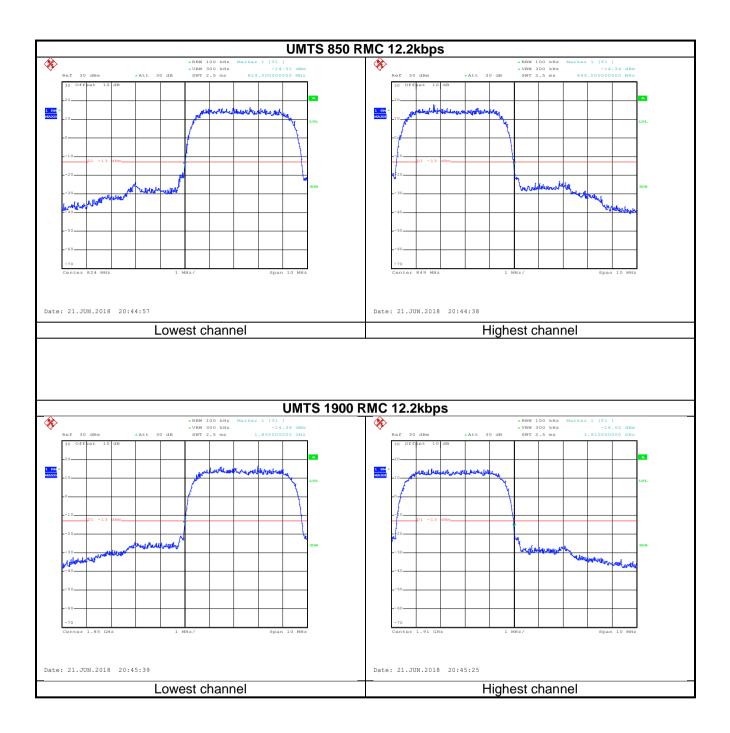
Band edge emission:



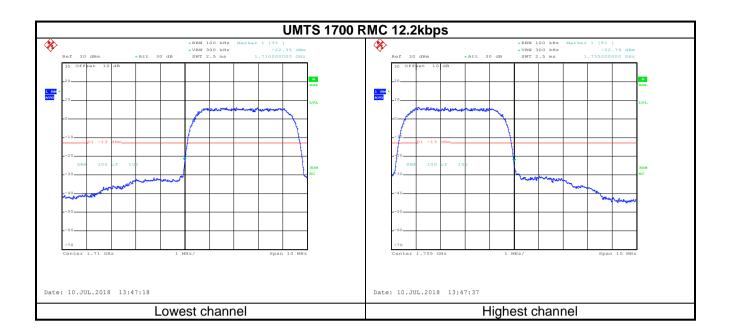














6.6 ERP, EIRP Measurement

Test Descriptions and			
Test Requirement:	FCC part 22.913(a)(2), FCC part 24.232(c), FCC part 27.50(d)(4)		
Test Method:	ANSI/TIA-603-D 2010		
Limit:	GSM850 7W: ERP, PCS1900 2W: EIRP		
Took ook in:	UMTS 850: 7W ERP, UMTS1900: 2W EIRP, UMTS1700: 1W EIRP		
Test setup:	Above 1GHz Test Receiver		
Test Procedure:	 The EUT was placed on an non-conductive turntable using a non-conductive support. The radiated emission at the fundamental frequency was measured at 3 m with a test antenna and EMI spectrum analyzer. During the measurement, the EUT was communication with the station. The highest emission was recorded with the rotation of the turntable and the lowering of the test antenna from 4m to 1m. The reading was recorded and the field strength (E in dBuV/m) was calculated. ERP in frequency band 824.2 –848.80.8MHz were measured using a substitution method. The EUT was replaced by dipole antenna connected, the S.G. output was recorded and ERP was calculated as follows: ERP = S.G. output (dBm) + Antenna Gain (dBd) – Cable Loss (dB) EIRP in frequency band 1850.2 –1909.8MHz were measured using a substitution method. The EUT was replaced by or horn antenna connected, the S.G. output was recorded and EIRP was calculated as follows: EIRP = S.G. output (dBm) + Antenna Gain (dBi) – Cable Loss (dB) The worst case was relating to the conducted output power. 		
Test Instruments:	Refer to section 5.8 for details		
Test mode:	Refer to section 5.3 for details		
Test results:	Passed		





Measurement Data (worst case):

EUT mode	Channel	EUT Pol.	Antenna Pol.	ERP(dBm)	Limit (dBm)	Result
GSM850	128	Н	V	29.92		
GOIVIOOU	120	П	Н	26.64		
EGPRS 850	128	Н	V	25.23	38.45	Door
EGPRS 650	120	П	Н	26.97	36.45	Pass
UMTS 850 12.2k	4183	Н	V	13.67		
RMC	4103	П	Н	13.01		
EUT mode	Channel	EUT Pol.	Antenna Pol.	EIRP(dBm)	Limit (dBm)	Result
PCS1900	810	Н	V	23.13		
PCS 1900		010	П	Н	23.12	
EGPRS 1900	512	Н	V	21.68	33	Pass
EGPRS 1900	312	П	Н	20.92	33	Pass
UMTS 1900	0262	Н	V	19.16		
12.2k RMC	9262	П	Н	18.46		
EUT mode	Channel	EUT Pol.	Antenna Pol.	EIRP(dBm)	Limit (dBm)	Result
UMTS 1700	1513	Н	V	20.25	30.00	Pass
12.2k RMC		11	Н	19.44	30.00	rass



6.7 Field strength of spurious radiation measurement

Test Requirement:	FCC part 22.917(a), FCC part 24.238(a), FCC part 27.53(h)		
Test Method:	ANSI/TIA-603-D 2010		
Limit:	-13dBm		
Test setup:	Below 1GHz Test Receiver Test Receiver Ground Reference Plane		
Test Procedure:	 The EUT was placed on an non-conductive turntable using a non-conductive support. The radiated emission at the fundamental frequency was measured at 3 m with a test antenna and EMI spectrum analyzer. During the tests, the antenna height and the EUT azimuth were varied in order to identify the maximum level of emissions from the EUT. This maximization process was repeated with the EUT positioned in each of its three orthogonal orientations. The frequency range up to tenth harmonic was investigated for each of three fundamental frequency (low, middle and high channels). Once spurious emission was identified, the power of the emission was determined using the substitution method. The spurious emissions attenuation was calculated as the difference between radiated power at the fundamental frequency and the spurious emissions frequency. ERP / EIRP = S.G. output (dBm) + Antenna Gain(dB/dBi) – Cable Loss (dB) 		
Test Instruments:	Refer to section 5.8 for details		
Test mode:	Refer to section 5.3 for details.		
Test results:	Passed		





Measurement Data (worst case):

		GSM850			
		Lowest channel			
[Spurious	Emission	Limeit (alDine)	Daguit	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
1648.40	Vertical	-35.76			
2472.60	V	-40.79	-13.00	Pass	
3296.80	V	-44.98			
1648.40	Horizontal	-33.23			
2472.60	Н	-39.16	-13.00	Pass	
3296.80	Н	-42.64			
		Middle channel			
Fraguency (MUz)	Spurious	Emission	Limit (dDm)	Result	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Resuit	
1673.20	Vertical	-31.92			
2509.80	V	-40.80	-13.00	Pass	
3346.40	V	-46.15			
1673.20	Horizontal	-31.16			
2509.80	Н	-43.71	-13.00	Pass	
3346.40	Н	-41.89			
		Highest channel			
Fraguency (MUz)	Spurious	Emission	Limit (dDm)	D !!	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
1697.60	Vertical	-30.57			
2546.40	V	-37.43	-13.00	Pass	
3395.20	V	-44.62			
1697.60	Horizontal	-30.59			
2546.40	Н	-37.45	-13.00	Pass	
3395.20	Н	-40.89			

Remark:

^{1.} The emission levels of below 1 GHz are very lower than the limit and not show in test report.





	Lowest channel			
	LOWEST CHAINIEL			
Spurious	Emission	Limit (dBm)	Result	
Polarization	Level (dBm)	Lilliit (dbill)	Result	
Vertical	-45.66	12.00	Pass	
V	-34.05	-13.00	Pass	
Horizontal	-39.01	42.00	Dees	
Н	-33.70	-13.00	Pass	
	Middle channel			
Spurious	Emission	Limit (dDm)	Result	
Polarization	Level (dBm)	Limit (abm)		
Vertical	-44.85	42.00	Door	
V	-30.90	-13.00	Pass	
Horizontal	-40.71	42.00	Dees	
Н	-31.60	-13.00	Pass	
	Highest channel			
Spurious	Emission	Limit (dDm)	Dani II	
Polarization	Level (dBm)	Limit (abm)	Result	
Vertical	-45.63	12.00	Doos	
V	-33.53	-13.00	Pass	
Horizontal	-43.43	12.00	Dese	
Н	-33.79	-13.00	Pass	
	Vertical V Horizontal H Spurious Polarization Vertical V Horizontal H Spurious Polarization Vertical V Horizontal H H H Spurious Polarization Vertical V Horizontal	Vertical -45.66 V -34.05 Horizontal -39.01 H -33.70 Middle channel Spurious Emission Polarization Level (dBm) Vertical -44.85 V -30.90 Horizontal -40.71 H -31.60 Highest channel Spurious Emission Polarization Level (dBm) Vertical -45.63 V -33.53 Horizontal -43.43	Vertical -45.66 -13.00 V -34.05 -13.00 Horizontal -39.01 -13.00 H -33.70 -13.00 Middle channel Spurious Emission Limit (dBm) Vertical -44.85 -13.00 V -30.90 -13.00 Horizontal -40.71 -13.00 Highest channel -13.00 Limit (dBm) Polarization Level (dBm) Limit (dBm) Vertical -45.63 -13.00 Vortical -45.63 -13.00 Horizontal -43.43 -13.00	

^{1.} The emission levels of below 1 GHz are very lower than the limit and not show in test report.





	WCD	MA BAND V 12.2k RN	IC		
		Lowest channel			
	Spurious	Emission	Line it (dDne)	Daguilt	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
1652.80	Vertical	-53.64			
2479.20	V	-43.83	-13.00	Pass	
3305.60	V	-51.21			
1652.80	Horizontal	-52.98			
2479.20	Н	-51.93	-13.00	Pass	
3305.60	Н	-51.08			
<u>.</u>		Middle channel			
Fragues and (MILE)	Spurious	Emission	Line it (dDne)	Desuit	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
1673.20	Vertical	-54.25			
2509.80	V	-50.61	-13.00	Pass	
3346.40	V	-51.13			
1673.20	Horizontal	-51.98			
2509.80	Н	-46.43	-13.00	Pass	
3346.40	Н	-50.69			
·		Highest channel			
Fraguency (MHz)	Spurious	Emission	Limit (dDm)	Result	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
1693.20	Vertical	-49.49			
2539.80	V	-48.68	-13.00	Pass	
3386.40	V	-50.97			
1693.20	Horizontal	-50.58			
2539.80	Н	-48.14	-13.00	Pass	
3386.40	Н	-51.56]		

^{1.} The emission levels of below 1 GHz are very lower than the limit and not show in test report.





	WCD	MA Band II 12.2k RM	IC			
		Lowest channel				
Fraguency (MUz)	Spurious	Emission	Limit (dDm)	Result		
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result		
3704.80	Vertical	-44.73	-13.00	Door		
5557.20	V	-44.75	-13.00	Pass		
3704.80	Horizontal	-38.62	12.00	Dese		
5557.20	Н	-44.23	-13.00	Pass		
Middle channel						
Fraguency (MILIT)	Spurious Emission		Limit (dDm)	Result		
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Kesuit		
3760.00	Vertical	-40.34	-13.00	Dese		
5640.00	V	-43.60	-13.00	Pass		
3760.00	Horizontal	-37.73	12.00	Door		
5640.00	Н	-43.63	-13.00	Pass		
		Highest channel				
Fraguency (MILIT)	Spurious	Emission	Limit (dDm)	Result		
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result		
3815.20	Vertical	-39.72	12.00	Door		
5722.80	V	-43.80	-13.00	Pass		
3815.20	Horizontal	-38.18	12.00	Door		
5722.80	Н	-44.41	-13.00	Pass		
Remark:						

The emission levels of below 1 GHz are very lower than the limit and not show in test report.





	WCDI	MA Band IV 12.2k RM	мс			
		Lowest channel				
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result		
Frequency (MHZ)	Polarization	Level (dBm)	LIIIII (UDIII)	Result		
3424.40	Vertical	-48.58	-13.00	Pass		
5136.60	V	-44.18	-13.00	Pass		
3424.40	Horizontal	-42.50	42.00	Dese		
5136.60	Н	-45.18	-13.00	Pass		
Middle channel						
Fraguency (MILIT)	Spurious	Emission	Limit (dDm)	Dooult		
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result		
3464.80	Vertical	-46.48	-13.00	Pass		
5197.20	V	-45.75	-13.00	Pass		
3464.80	Horizontal	-42.20	42.00	Dese		
5197.20	Н	-45.42	-13.00	Pass		
		Highest channel				
Fraguency (MILIT)	Spurious	Emission	Limit (dDm)	Result		
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result		
3505.20	Vertical	-47.00	12.00	Door		
5257.80	V	-44.26	-13.00	Pass		
3505.20	Horizontal	-42.10	42.00	Dese		
5257.80	Н	-43.57	-13.00	Pass		
Remark:			<u> </u>			

^{1.} The emission levels of below 1 GHz are very lower than the limit and not show in test report.



6.8 Frequency stability V.S. Temperature measurement

Test Requirement:	FCC Part 22.355, FCC Part 24.235, FCC Part 27.54, FCC Part 2.1055(a)(1)(b)
Test Method:	ANSI/TIA-6-3-D 2010
Limit:	±2.5 ppm
Test setup:	SS Divider Temperature & Humidity Chamber Power Source
Test procedure:	 The equipment under test was connected to an external DC power supply and input rated voltage. RF output was connected to a frequency counter or spectrum analyzer via feed through attenuators. The EUT was placed inside the temperature chamber. Set the spectrum analyzer RBW low enough to obtain the desired frequency resolution and measure EUT 25°C operating frequency as reference frequency. Turn EUT off and set the chamber temperature to -30°C. After the temperature stabilized for approximately 30 minutes recorded the frequency. Repeat step measure with 10°C increased per stage until the highest temperature of +50°C reached
Test Instruments:	Refer to section 5.8 for details
Test mode:	Refer to section 5.3 for details
Test results:	Passed





Measurement Data (the worst channel):

Refe	erence Frequency: GS	M850 Middle	channel=190 chai	nnel=836.6MHz	
Power supplied	Tomporeture (°C)	Freq	uency error	Limit (nnm)	Dogult
(Vdc)	Temperature (°C)	Hz	Ppm	Limit (ppm)	Result
	-30	176	0.210375		
	-20	157	0.187664		
	-10	138	0.164953		
	0	127	0.151805		
3.80	10	116	0.138656	±2.5	Pass
	20	144	0.172125		
	30	141	0.168539		
	40	130	0.155391		
	50	119	0.142242		
Refe	rence Frequency: PC	S1900 Middle	e channel=661 cha	nnel=1880MHz	
Power supplied	Temperature (°C)	Freq	uency error	Limit (ppm)	Result
(Vdc)	remperature (c)	Hz	Ppm	Еппі (рріп)	Nesuit
	-30	181	0.096277		
	-20	158	0.084043		
	-10	144	0.076596		
	0	132	0.070213		
3.80	10	128	0.068085	±2.5	Pass
	20	119	0.063298		
	30	110	0.058511		
	40	141	0.075000		
	50	149	0.079255		





Power supplied	T (00)	Fred	uency error		
(Vdc)	Temperature (°C)	Hz	Ppm	Limit (ppm)	Result
	-30	172	0.205594		
	-20	153	0.182883	1	
	-10	134	0.160172		
	0	123	0.147024		
3.80	10	112	0.133875	±2.5	Pass
	20	141	0.168539		
	30	137	0.163758		
	40	126	0.150610		
	50	115	0.137461		
Refere	ence Frequency: EGP	RS 1900 Mid	dle channel=661 ch	nannel=1880MHz	
Power supplied	Temperature (°C)	Freq	uency error	Limit (ppm)	Result
(Vdc)	remperature (c)	Hz	Ppm	Еши (ррш)	rvesuit
	-30	177	0.094149		
	-20	154	0.081915		
	-10	140	0.074468		
	0	158	0.084043		
3.80	10	124	0.065957	±2.5	Pass
	20	115	0.061170		
	30	106	0.056383		
	40	137	0.072872		
	50	145	0.077128	1	





	quency: WCDMA BAN		uency error		7010111112
Power supplied (Vdc)	Temperature (°C)	Hz	Ppm	Limit (ppm)	Result
	-30	171	0.204399		
	-20	144	0.172125		
	-10	137	0.163758		
	0	124	0.148219		
3.80	10	110	0.131485	±2.5	Pass
	20	165	0.197227		
	30	164	0.196032		
	40	140	0.167344		
	50	147	0.175711		
Reference Fre	quency: WCDMA BAN	ID II 12.2k RI	MC Middle channe	l=9400 channel=1	B80MHz
Power supplied	Tomporature (°C)	Fred	luency error	Limit (nnm)	Dogult
(Vdc)	Temperature (°C)	Hz	Ppm	Limit (ppm)	Result
	-30	192	0.102128		
	-20	154	0.081915		
	-10	145	0.077128		
	0	167	0.088830		
3.80	10	147	0.078191	±2.5	Pass
	20	129	0.068617		
	30	150	0.079787		
	40	138	0.073404		
	50	154	0.081915		
Reference F	requency: UMTS1700	12.2k RMC I	Middle channel=14	13 channel=1732.	6MHz
Power supplied	Temperature (°C)		luency error	Limit (ppm)	Result
(Vdc)	Tomporatare (e)	Hz	Ppm	Ziiiii (ppiii)	rtocait
	-30	174	0.100427		
	-20	144	0.083112		
	-10	145	0.083689		
	0	128	0.073877		
3.80	10	110	0.063488	±2.5	Pass
	20	146	0.084266		
	30	170	0.098118		
	40	160	0.092347		
	50	131	0.075609		



6.9 Frequency stability V.S. Voltage measurement

Test Requirement:	FCC Part 22.355, FCC Part 24.235, FCC Part 27.54, FCC Part 2.1055(d)(2)
Test Method:	ANSI/TIA-603-D 2010
Limit:	±2.5ppm
Test setup:	SS EUT Divider Temperature & Humidity Chamber Power Source
Test procedure:	 Set chamber temperature to 25°C. Use a variable DC power source to power the EUT and set the voltage to rated voltage. Set the spectrum analyzer RBW low enough to obtain the desired frequency resolution and recorded the frequency. Reduce the input voltage to specify extreme voltage variation (+/-15%) and endpoint, record the maximum frequency change.
Test Instruments:	Refer to section 5.8 for details
Test mode:	Refer to section 5.3 for details
Test results:	Passed





Measurement Data (the worst channel):

	E worst channer).	214252 14: 1 ::	1 1 100 1	1 000 0141	
Refer	ence Frequency: G	SM850 Middle	channel=190 chan	nel=836.6MHz	
Temperature (℃)	Power supplied	Frequ	Frequency error		Result
remperature (C)	(Vdc)	Hz	Ppm	Limit (ppm)	Nesuit
	4.35	87	0.103992		
25	3.80	80	0.095625	±2.5	Pass
	3.55	70	0.083672		
Refer	ence Frequency: PC	CS1900 Middle	channel=661 cha	nnel=1880MHz	
Temperature (°C)	Power supplied	Frequ	iency error	Limit (nnm)	Result
remperature (C)	(Vdc)	Hz	Ppm	Limit (ppm)	Result
	4.35	92	0.048936		
25	3.80	76	0.040426	±2.5	Pass
	3.55	82	0.043617		
Referer	nce Frequency: EGF	RS 850 Middle	e channel= 190 ch	annel=836.6MHz	
Temperature (℃)	Power supplied	Frequ	iency error	Limit (ppm)	Result
remperature (C)	(Vdc)	Hz	Ppm	Limit (ppm)	Result
	4.35	94	0.112360		
25	3.80	86	0.102797	±2.5	Pass
	3.55	68	0.081281		
Referen	ce Frequency: EGP	RS 1900 Midd	le channel= 661 ch	nannel=1880MHz	
Temperature (℃)	Power supplied	Frequency error		Limit (ppm)	Result
remperature (C)	(Vdc)	Hz	Ppm	Limit (ppin)	Result
	4.35	83	0.099211		
25	3.80	72	0.086063	±2.5	Pass
	3.55	84	0.100406		
Note: Only the worst cas	e shown in the report.				





Reference	Frequency: UMTS 8	50 12.2k RMC M	iddle channel=41	83 channel=836.6	6MHz
Tamanarahura (°C)	Power supplied	Freque	ncy error	Limit (nnm)	D "
Temperature (°C)	(Vdc)	Hz	Ppm	Limit (ppm)	Result
	4.35	86	0.102797		
25	3.80	92	0.109969	±2.5	Pass
	3.55	65	0.077695		
Reference l	Frequency: UMTS 19	900 12.2k RMC N	liddle channel=9	400 channel=1880	OMHz
Tomporatura (°C)	Power supplied	Frequency error		Limit (nnm)	Result
Temperature (°C)	(Vdc)	Hz	Ppm	Limit (ppm)	Result
	4.35	80	0.042553		
25	3.80	83	0.044149	±2.5	Pass
	3.55	72	0.038298		
Reference F	requency: UMTS170	00 12.2k RMC Mi	ddle channel=14	13 channel=1732.	6MHz
Tomorous (°C)	Power supplied	Frequer	ncy error	Limit (nnm)	Result
Temperature (°C)	(Vdc)	Hz	Ppm	Limit (ppm)	Result
	4.35	92	0.053099		
25	3.80	86	0.049636	2.5	Pass
	3.55	59	0.034053		
25 Note: Only the worst cas	3.80 3.55	86	0.049636	2.5	